

Notice of References Cited	Application/Control No. 10/528,097	Applicant(s)/Patent Under Reexamination KITAKADO, JUN	
	Examiner <i>KP</i> Kamran Afshar, 571-272-7796	Art Unit 2617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,966,186	10-1999	Shigihara et al.	348/570
*	B	US-6,836,244	12-2004	Kitakado, Jun	342/377
*	C	US-5,486,843	01-1996	Otting et al.	345/35
*	D	US-6,151,515	11-2000	Deguchi, Kazuo	455/566
*	E	US-2004/0235511	11-2004	Nakao, Seigo	455/522
*	F	US-2006/0234653	10-2006	Yamamoto, Naoki	455/121
*	G	US-7,133,446	11-2006	Fulton, Paul	375/224
*	H	US-6,907,276	06-2005	Toba, Hiroyuki	455/566
*	I	US-5,797,083	08-1998	Anderson, Paul R.	455/25
*	J	US-2004/0014443	01-2004	Nakao et al.	455/130
*	K	US-2004/0165685	08-2004	Kitakado, Jun	375/343
*	L	US-6,035,183	03-2000	Todd et al.	455/226.2
*	M	US-6,393,307	05-2002	Kim, Hoo-Ja	455/566

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002135198 A	05-2002	Japan	HOSHINA, TAKAYA	H04B 7/26
	O	JP 09205390 A	08-1997	Japan	OZAKI et al.	H04B 7/02
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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